## PATENT APPLICATION

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IN THE

## UNITED STATES PATENT AND TRADEMARK OFFICE

TRADE Inventor(s):

Stan E. LEIGH, et al.

C nfirmation No.:

**Application No.: 10/621,484** 

**Examiner:** 

Filing Date:

07/16/03

W) under 27 CER 1 07/h) ---

**Group Art Unit:** 

Title:

A FUSE STRUCTURE

**COMMISSIONER FOR PATENTS** Washington, D.C. 20231

INFORMATION DISCLOSURE STATEMENT

Sir:

This Information Disclosure Statement is submitted:

W,	(Within three months of filing national application; or date of entry of national application; or before mailing date of first office action on the merits; whichever occurs last)
( )	under 37 CFR 1.97 (c) together with either a:  ( ) Statement under 37 CFR 1.97(e), or  ( ) a \$180.00 fee under 37 CFR 1.17(p), or  (After the CFR 1.97 (b) time period, but before final action or notice of allowance, whichever occurs first)
( )	under 37 CFR 1.97 (d) together with a:  ( ) Statement under 37 CFR 1.97(e)(1) or (2), and  ( ) a \$180.00 fee set forth in 37 CFR 1.17(p).  (Filed after final action, a notice of allowance, on or before before payment of the issue fee)

Please charge to Deposit Account 08-2025 the sum of \$0.00 . At any time during the pendency of this application, please charge any fees required or credit any overpayment to Deposit Account 08-2025 pursuant to 37 CFR 1.25.

- Applicant(s) submit herewith Form PTO 1449 Information Disclosure Citation together with copies, of patents, publications or other information of which applicant(s) are aware, which applicant(s) believe(s) may be material to the examination of this application and for which there may be a duty to disclose in accordance with 37 CFR 1.56.
- ( ) A concise explanation of the relevance of foreign language patents, foreign language publications and other foreign language information listed on PTO Form 1449, as presently understood by the individuals(s) designated in 37 CFR 1.56 (c) most knowledgeable about the content is given on the attached sheet, or where a foreign language patent is cited in a search report or other action by a foreign patent office in a counterpart foreign application, an English language version of the search report or action which indicates the degree of relevance found by the foreign office is listed on form PTO 1449 and is enclosed herewith.

It is requested that the information disclosed herein be made of record in this application.

(X) I hereby certify that this correspondence is being deposited with the United States Postal Service	Respectfully submitted,
as first class mail in an envelope addressed to: Commissioner for Patents, Washington, D.C.	Stan E. LEIGH, et al.
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( ) I hereby certify that this paper is being transmitted to the Patent and Trademark Office facsimile numberon	John P. Wagner, Jr.
Number of pages:	Attorney/Agent for Applicant(s)
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## **FOREIGN PATENT DOCUMENTS**

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## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

	10	H. CERIC, et al.; "ELECTROMIGRATION INDUCED EVOLUTION OF VOIDS IN CURRENT CROWDING AREAS OF INTERCONNECTS"; 2002 IEEE; Proceedings of 9th IPFA 2002, Singapore; Pages140-144.			
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